Se	arcn Not	res	-

Application/Control No.	Applicant(s)/Patent under Reexamination
10/754,550	CHO, JANG-HO
Examiner	Art Unit
Benjamin P. Geib	2181

	SEARCHED			
Class	Subclass	Date	Examiner	
712	205	4/16/2007	BPG	
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
			_
PGPUB te	ext search	4/16/2007	BPG

	SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
<u> i</u> .	DATE	EXMR	
Updated EAST search	4/16/2007	BPG	
NPL search (Google Scholar, IEEE Xplore)	4/16/2007	BPG	
Inventor name search	4/9/2007	BPG	